

Your paper ID is listed below

Sep. 6													
Time	Oral Presentation												
14:00 - 15:20	B-1	148	C-1	1	D-1	126	Keynote Prof. Kim	F-1	55				
		52		94		115			152				
		150	Keynote Prof. Sommer			15			154				
		11				125			23				
15:50 - 17:30	B-2	51	C-2	114	D-2	132	E-2	Keynote Prof. Zahwi					
		63		98		129							
		5		155		87			116				
		49	Keynote Dr. Ina			112		F-2	157				
		27				-			160				
Sep. 7													
Time	Oral Presentation												
10:30 - 12:10	B-3	104	Keynote Prof. Gao		D-3	142	E-3	F-3	159				
		107				54			110				
		134	C-3	106		147			37				
		17		69		31			35				
		19		117		144			30				
13:30 - 14:50													
Poster Presentation													
15:20 - 17:00	B-4	161	Keynote Prof. Jablonski		D-4	70	E-4	F-4	149				
		43				71			81				
		135	C-4	85		68			76				
		131		88		26			95				
		-		93		62			143				
Sep. 8													
Time	Oral Presentation												
9:00 - 10:20	B-5	39	C-5	65	D-5	113	E-5	F-5	22				
		28		99		21			29				
		100		127		138			79				
		36		141		72			-				
10:30 - 11:50	B-6	86	C-6	133	D-6	75	E-6	F-6	103				
		158		130		136			105				
		151		108		92			-				
		-		-		128			-				

**B-1** 3-D Surface Texture and its Micro Characteristics  
**C-1** Optical Measurement for Geometrical Quantity Evaluation (1)  
**D-1** Advanced Optoelectronic Sensors & Instrument (1)  
**E-1** Ultra Precision Length Measurement  
**F-1** Macrogeometric Features & Uncertainty Evaluation

**B-2** Gear Metrology  
**C-2** MEMS/MOEMS application in Measurement field  
**D-2** Advanced Optoelectronic Sensors & Instrument (2)  
**E-2** CMM Metrology (1)  
**F-2** Uncertainty Evaluation & Traceability (1)

**B-3** Optical Measurement for Geometrical Quantity Evaluation (2)  
**C-3** Pre-, In-, Post process measurement  
**D-3** Quality Control  
**E-3** CMM Metrology (2)  
**F-3** Uncertainty Evaluation and Traceability (2)

**B-4** Intelligent Micro and Nano Metrology (1)  
**C-4** Analytical Method for Uncertainty Evaluation  
**D-4** Optical Measurement for Geometrical Quantity Evaluation (3)  
**E-4** CMM Metrology (3)  
**F-4** Tolerance, Testing, Test Planning

**B-5** Novel Method for Medical and Biological Measurement  
**C-5** Machine Vision and Image Processing  
**D-5** Intelligent Micro and Nano Metrology (2)  
**E-5** Nano Photonics in Intelligent Measurement  
**F-5** Intelligent Measurement Algorithm and Simulation (1)

**B-6** X-Ray Application for 3-D Measurement  
**C-6** Optical Measurement for Geometrical Quantity Evaluation (4)  
**D-6** Pre-, In-, Post process measurement (2)  
**E-6** Geometrical Product Specification and Form Test  
**F-6** Intelligent Measurement Algorithm and Simulation (2)